Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10614997 on November 03, 2005

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7   714/724      (1 OR, 6 XR)
         Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
         714/699          PULSE OR DATA ERROR HANDLING
         714/724          .Digital logic testing

6   324/158.1    (4 OR, 2 XR)
         Class   324 :  ELECTRICITY:  MEASURING AND TESTING
         324/158.1       MISCELLANEOUS

6   324/754      (4 OR, 2 XR)
         Class   324 :  ELECTRICITY:  MEASURING AND TESTING
         324/500          FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                           ELECTRIC COMPONENTS
         324/537          .Of individual circuit component or element
         324/754          ..With probe elements

6   324/765      (5 OR, 1 XR)
         Class   324 :  ELECTRICITY:  MEASURING AND TESTING
         324/500          FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                           ELECTRIC COMPONENTS
         324/537          .Of individual circuit component or element
         324/765          ..Test of semiconductor device

6   714/733      (0 OR, 6 XR)
         Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
         714/699          PULSE OR DATA ERROR HANDLING
         714/724          .Digital logic testing
         714/733          ..Built-in testing circuit (BILBO)

5   209/573      (0 OR, 5 XR)
         Class   209 :  CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS

         209/509          SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND
                           APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING,
                           ETC.) FOR SORTING ANY ITEMS
         209/552          .Condition responsive means controls separating
                           means
         209/571          ..Electrical test sensing property of item
         209/573          ...Electrical component tested

5   324/758      (2 OR, 3 XR)
         Class   324 :  ELECTRICITY:  MEASURING AND TESTING
         324/500          FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                           ELECTRIC COMPONENTS
         324/537          .Of individual circuit component or element
         324/754          ..With probe elements
         324/758          ...Probe alignment or positioning

5   324/763      (4 OR, 1 XR)
         Class   324 :  ELECTRICITY:  MEASURING AND TESTING
         324/500          FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                           ELECTRIC COMPONENTS
         324/537          .Of individual circuit component or element
         324/763          ..DUT including test circuit

3   324/73.1     (0 OR, 3 XR)
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       Class  324 : ELECTRICITY:  MEASURING AND TESTING
       324/73.1       PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

  3  365/201      (1 OR, 2 XR)
       Class  365 :  STATIC INFORMATION STORAGE AND RETRIEVAL
       365/189.01    READ/WRITE CIRCUIT
       365/201       .Testing

  2  257/E23.149  (0 OR, 2 XR)
       Class  257 :  ACTIVE SOLID-STATE DEVICES
       257/E23.139   ...Liquid at normal operating temperature of
                         device (EPO)
       257/E23.141   .Arrangements for conducting electric current
                         within device in operation from one component to
another,
                         interconnections, e.g., wires, lead frames (EPO)
       257/E23.142   ..Including external interconnections
                         consisting of multilayer structure of conductive and
                         insulating layers inseparably formed on semiconductor
body
                         (EPO)
       257/E23.146   ...With adaptable interconnections (EPO)
       257/E23.149   ....Comprising fuses, i.e., connections having
                         their state changed from conductive to nonconductive
(EPO)


  2  324/760      (0 OR, 2 XR)
       Class  324 :  ELECTRICITY:  MEASURING AND TESTING
       324/500       FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                         ELECTRIC COMPONENTS
       324/537       .Of individual circuit component or element
       324/754       ..With probe elements
       324/760       ...With temperature control

  2  414/416.01   (0 OR, 2 XR)
       Class  414 :  MATERIAL OR ARTICLE HANDLING
       414/403       DEVICE FOR EMPTYING PORTABLE RECEPTACLE
       414/416.01    .Nongravity type

  2  702/119      (2 OR, 0 XR)
       Class  702 :  DATA PROCESSING: MEASURING, CALIBRATING, OR
                         TESTING
       702/108       TESTING SYSTEM
       702/117       .Of circuit
       702/119       ..Including program initialization (e.g.,
                         program loading) or code selection (e.g., program
creation)


  2  714/32       (1 OR, 1 XR)
       Class  714 :  ERROR DETECTION/CORRECTION AND FAULT
                         DETECTION/RECOVERY
       714/100       DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

       714/1         .Reliability and availability
       714/25        ..Fault locating (i.e., diagnosis or testing)

       714/32        ...Particular stimulus creation

  2  714/718      (1 OR, 1 XR)
       Class  714 :  ERROR DETECTION/CORRECTION AND FAULT
                         DETECTION/RECOVERY
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        714/699        PULSE OR DATA ERROR HANDLING
        714/718        .Memory testing

2   714/719       (1 OR, 1 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/718        .Memory testing
        714/719        ..Read-in with read-out and compare

2   714/8         (2 OR, 0 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                           DETECTION/RECOVERY
        714/100        DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

        714/1          .Reliability and availability
        714/2          ..Fault recovery
        714/3          ...By masking or reconfiguration
        714/5          ....Of memory or peripheral subsystem
        714/8          .....Isolating failed storage location (e.g.,
                           sector remapping)

2   716/4         (0 OR, 2 XR)
        Class    716 :   DATA PROCESSING:  DESIGN AND ANALYSIS OF
                           CIRCUIT OR SEMICONDUCTOR MASK
        716/1          CIRCUIT DESIGN
        716/4          .Testing or evaluating
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